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Sheet	1	of	1

Complete if Known	
Application Number	10/045,055
Filing Date	January 15, 2002
First Named Inventor	Benoudiz
Group Art Unit	2133
Examiner Name	
Attorney Docket Number	24773 Previously V02/16

U.S. PATENT DOCUMENTS

Examiners Initials	Cite No.[1]	U.S. Patent Document Number	Kind Code[2] (if known)	Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, columns, lines, Where Relevant Passages or Relevant Figures Appear
CK	AA	4,937,765		Shupe et al	06-26-1990	
CK	AB	5,202,889		Aharon et al	04-13-1993	
CK	AC	5,633,812		Allen et al	05-27-1997	
CK	AD	5,844,909		Wakui	12-01-1998	
CK	AE	6,044,214		Kimura et al	03-28-2000	
CK	AF	6,059,451		Scott et al	05-09-2000	

OTHER PRIOR ART – NON PATENT LITERATURE DOCUMENTS

Examiner Initials	Cite No.[1]	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial symposium, catalog, etc.) date, page(s), volume-issue number(s), publisher, city and/or country where published.	T[2]
CK	AG	Benjamin et al, A Study in Coverage-Driven Test Generation, DAC, 1999, pp. 970 – 975	
CK	AH	Debany Jr. et al, Design Verification Using Logic Tests, IEEE, 1992, pp. 17 – 24	
CK	AI	Moundanos, et al., Abstraction Techniques for Validation Coverage Analysis and Test Generation, IEEE Transactions on Computers, Vol. 47, No. 1, January 1998, pp. 2 – 14	
CK	AJ	Piwowarski, Coverage Measurement Experience During Function Test, IEEE Proc. 15th Int. Conf. Software Engineering, 1993, pp 287 – 301	
CK	AK	Greggain et al, Fault Grading, A Measure of Logic Simulation Integrity, Proc. 2nd Annual IEEE ASIC Seminar and Exhibit, 1989, pp 9-2.1 – 9-2.4	
CK	AL	Sneed, State Coverage of Embedded Realtime Programs, Proc. 2nd Workshop on Software Testing, Verification & Analysis, 1988, pp 245	

Examiner Signature	Chuck Kendall	Date Considered	2/13/06

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